IEEE Std C57.98-1993
(Revision of
IEEE Std C57.98-1986)

IEEE Guide for Transformer Impulse Tests

Sponsor

Transformers Committee
of the
IEEE Power Engineering Society

Correction Sheet

Issued 16 January 1998

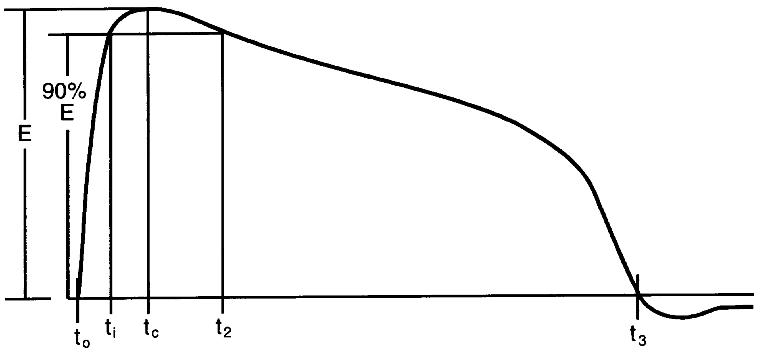
The following corrections should be made to the standard:

Page 3: Change the two references to IEEE Std C57.12.90-1993 to IEEE Std C57.12.00-1993. The impacted paragraphs should read as follows:

A wave traveling along the line might flash over an insulator after the crest of the wave has been reached. This wave is simulated by the chopped wave that is chosen to be of magnitude as defined in IEEE Std C57.12.00-1993. It is shown by curve “b.”

The selection of the type and number of test waves is determined by the test specification. These various test specifications may include a number of purchaser specifications in addition to the ones required by IEEE Std C57.12.00-1993.

Page 33: The third callout below Figure 34 should be 1000 μs rather than 200 μs, as shown on the following page.



$t_c - t_o > 100\ \mu s$

$t_2 - t_i \geqq 200\ \mu s$

$t_3 - t_o \geqq 1000\ \mu s$

E = REQUIRED BSL

Figure 34—Switching impulse voltage wave shape

Page 35: Add a reference to 3.4.1 at the end of the second paragraph of 3.4. The paragraph should read as follows:

Figure 38 shows a typical test circuit used for switching impulse tests. The measurement devices in figure 38 include the voltage dividers and the oscilloscope or transient voltage recorder. These will be discussed in detail in 3.4.1.